

STN	Feritové jadrá. Návod na medze povrchových nerovnomerností. Časť 2: RM-jadrá.	STN EN 60424-2 35 8471
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Ferrite cores - Guidelines on the limits of surface irregularities - Part 2: RM-cores

Táto norma obsahuje anglickú verziu európskej normy.
This standard includes the English version of the European Standard.

Táto norma bola oznámená vo Vestníku ÚNMS SR č. 07/16

Obsahuje: EN 60424-2:2016, IEC 60424-2:2015

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rozmnožovať a rozširovať iba so súhlasom Úradu pre normalizáciu, metrológiu a skúšobníctvo SR.

English Version

**Ferrite cores - Guidelines on the limits of surface irregularities -
Part 2: RM-cores
(IEC 60424-2:2015)**

Noyaux ferrites - Lignes directrices relatives aux limites des
irrégularités de surface -
Partie 2: Noyaux RM
(IEC 60424-2:2015)

Ferritkerne - Leitfaden für Grenzwerte von sichtbaren
Beschädigungen der Kernoberfläche -
Teil 2: RM-Kerne
(IEC 60424-2:2015)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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EN 60424-2:2016**European foreword**

The text of document 51/1108/FDIS, future edition 2 of IEC 60424-2, prepared by IEC/TC 51 "Magnetic components and ferrite materials" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 60424-2:2016.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2016-10-08
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2019-01-08

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In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 60424-1	NOTE	Harmonized as EN 60424-1.
IEC 60424-2	NOTE	Harmonized as EN 60424-2.
IEC 60424-3	NOTE	Harmonized as EN 60424-3.
IEC 60424-4	NOTE	Harmonized as EN 60424-4.
IEC 60424-5	NOTE	Harmonized as EN 60424-5.



INTERNATIONAL STANDARD

NORME INTERNATIONALE

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INTERNATIONAL STANDARD

NORME INTERNATIONALE

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Part 2: RM-cores**

**Noyaux ferrites – Lignes directrices relatives aux limites des irrégularités de
surface –
Partie 2: Noyaux RM**

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

FERRITE CORES – GUIDELINES ON THE LIMITS OF SURFACE IRREGULARITIES –

Part 2: RM-cores

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International Standard IEC 60424-2 has been prepared by technical committee 51: Magnetic components and ferrite materials.

This second edition cancels and replaces the first edition published in 1997. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) addition of crystallites in 3.6 and of pores in 3.7.

The text of this standard is based on the following documents:

FDIS	Report on voting
51/1108/FDIS	51/1122/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 60424 series, published under the general title *Ferrite cores – Guidelines on the limits of surface irregularities*, can be found on the IEC website.

Future standards in this series will carry the new general title as cited above. Titles of existing standards in this series will be updated at the time of the next edition.

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- replaced by a revised edition, or
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FERRITE CORES – GUIDELINES ON THE LIMITS OF SURFACE IRREGULARITIES –

Part 2: RM-cores

1 Scope

This part of IEC 60424 provides guidelines on the allowable limits of surface irregularities applicable to RM-cores in accordance with the relevant generic specification.

This standard should be considered as a sectional specification useful in the negotiations between ferrite core manufacturers and customers about surface irregularities. Normative reference

2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

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